

TECHNICAL SPECIFICATION

**Photovoltaic (PV) modules – Test methods for the detection of potential-induced degradation –
Part 1: Crystalline silicon**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**PHOTOVOLTAIC (PV) MODULES –
TEST METHODS FOR THE DETECTION
OF POTENTIAL-INDUCED DEGRADATION –****Part 1: Crystalline silicon****FOREWORD**

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IEC TS 62804-1 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems. It is a Technical Specification.

This second edition cancels and replaces the first edition published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) A procedure specifically for measuring PID-polarization was added.
- b) A procedure specifically for measuring the extent of recovery of PID-polarization was added.

The text of this Technical Specification is based on the following documents:

Draft	Report on voting
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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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